INTEGRATED CIRCUITS

DATA SHEET

勝 特 力 材 料 886-3-5753170 胜特力电子(上海) 86-21-34970699 胜特力电子(深圳) 86-755-83298787 Http://www.100y.com.tw

74F139Dual 1-of-4 decoder/demultiplexer

Product specification

1990 Feb 23

IC15 Data Handbook





74F139

FEATURES

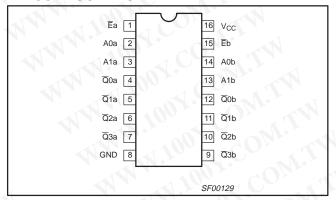
- Demultiplexing capability
- Two independent 1-of-4 decoders
- Multifunction capability

DESCRIPTION

The 74F139 is a high speed, dual 1-of-4 decoder/demultiplexer. This device has two independent decoders, each accepting two binary weighted inputs (A0n, A1n) and providing four mutually exclusive active-Low outputs ($\overline{Q}0n-\overline{Q}3n$). Each decoder has an active-Low Enable (\overline{E}). When \overline{E} is High, every output is forced High. The Enable can be used as the Data input for a 1-of-4 demultiplexer application.

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F139	5.3ns	13mA

PIN CONFIGURATION



ORDERING INFORMATION

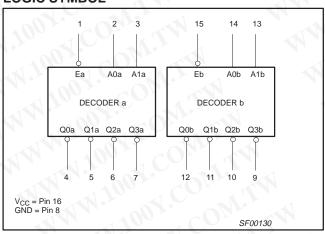
DESCRIPTION	COMMERCIAL RANGE V_{CC} = 5V ±10%, T_{amb} = 0°C to +70°C	PKG DWG#
16-pin plastic DIP	N74F139N	SOT38-4
16-pin plastic SO	N74F139D	SOT109-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

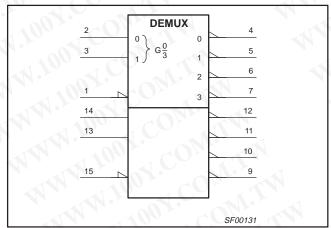
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Ana, Anb	Address inputs	1.0/1.0	20μA/0.6mA
Ea, Eb	Enable inputs (active Low)	1.0/1.0	20μA/0.6mA
Q0n−Q3n	Data outputs (active Low)	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20μA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL

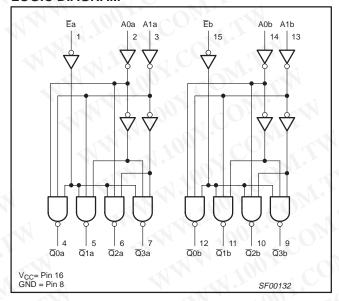


IEC/IEEE SYMBOL



74F139

LOGIC DIAGRAM



FUNCTION TABLE

	INPUTS	00_{2}		OUT	PUTS	
Ē	A0	A1	Q0	Q1	Q2	<u>Q</u> 3
Н	Х	X	HC	Ĥ	Н	Н
L	L	L	L	Н	Н	Н
L	Н	L	Н	L	Н	Н
L	L	Н	Н	H	L	Н
L	Н	Н	Н	Н	Ĥ	L

NOTES:
H = High voltage level
L = Low voltage level
X = Don't care

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to +V _{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

	4 CO (1) (1)	1 C	LIMITS		
SYMBOL	PARAMETER	MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0	Co		V
V _{IL}	Low-level input voltage	100	~O)	0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current	11/10	21 C	-1	mA
l _{OL}	Low-level output current		00 2.	20	mA
T _{amb}	Operating free-air temperature range	0		+70	°C

74F139

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

OVMDOL	A DOLLETTO	TEOT COMPLET	21/01	21 C	LIMITS		
SYMBOL	PARAMETER	TEST CONDITIO	DNS	MIN	TYP ²	MAX	UNIT
V	Link lovel outset valence	$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}	2.5			V
V _{OH}	High-level output voltage	$V_{IH} = MIN, I_{OH} = MAX$	±5%V _{CC}	2.7	3.4		V
V	Law layer output voltage	$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}		0.30	0.50	V
V _{OL}	Low-level output voltage	V _{IH} = MIN, I _{OL} = MAX	±5%V _{CC}	70	0.30	0.50	٧
V _{IK}	Input clamp voltage	$V_{CC} = MIN, I_I = I_{IK}$. 40	-0.73	-1.2	V
I _I	Input current at maximum input voltage	$V_{CC} = MAX, V_I = 7.0V$				100	μА
I _{IH}	High-level input current	$V_{CC} = MAX, V_I = 2.7V$		41	(00)	20	μА
I _{ILL}	Low-level input current	$V_{CC} = MAX, V_I = 0.5V$				-0.6	mA
los	Short-circuit output current ³	V _{CC} = MAX		-60	1.70	-150	mA
Icc	Supply current (total)	$V_{CC} = MAX$			13	20	mA

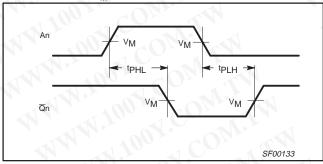
- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. All typical values are at $V_{CC} = 5V$, $T_{amb} = 25^{\circ}C$. Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

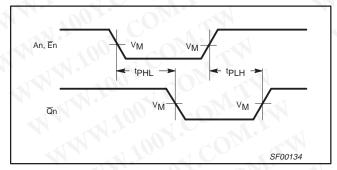
					LIMI	rs		70
SYMBOL	PARAMETER	TEST CONDITION	Т,	/ _{CC} = +5.0 _{amb} = +25 50pF, R _L =	°C	T _{amb} = 0°	.0V ± 10% C to +70°C R _L = 500Ω	UNIT
	M. THE	" NAV	MIN	TYP	MAX	MIN	MAX	
t _{PLH}	Propagation delay A0 ir A1 to Qna, Qnb	Waveform 1, 2	3.5 4.0	5.3 6.1	7.0 8.0	3.0 4.0	8.0 9.0	ns
t _{PLH}	Propagation delay En to Qna, Qnb	Waveform 2	3.5 3.0	5.4 4.7	7.0 6.5	3.5 3.0	8.0 7.5	ns

AC WAVEFORMS

For all waveforms, $V_M = 1.5V$



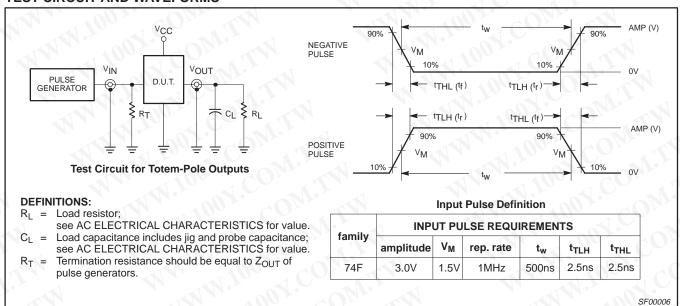
Waveform 1. **Propagation Delay for Inverting Outputs**



Waveform 2. **Propagation Delay for Non-Inverting Outputs**

74F139

TEST CIRCUIT AND WAVEFORMS



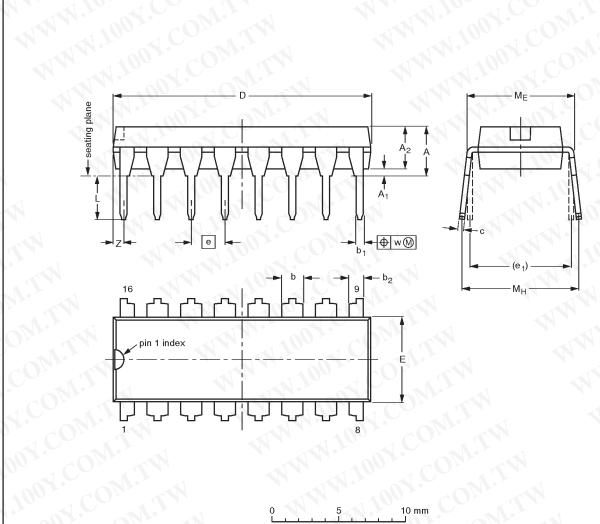
Philips Semiconductors Product specification

Dual 1-of-4 decoder/demultiplexer

74F139

DIP16: plastic dual in-line package; 16 leads (300 mil)

SOT38-4



scale

DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	b ₂	С	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.030

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE	1003	REFE	RENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE
SOT38-4	1700,	OD CON			92-11-17 95-01-14

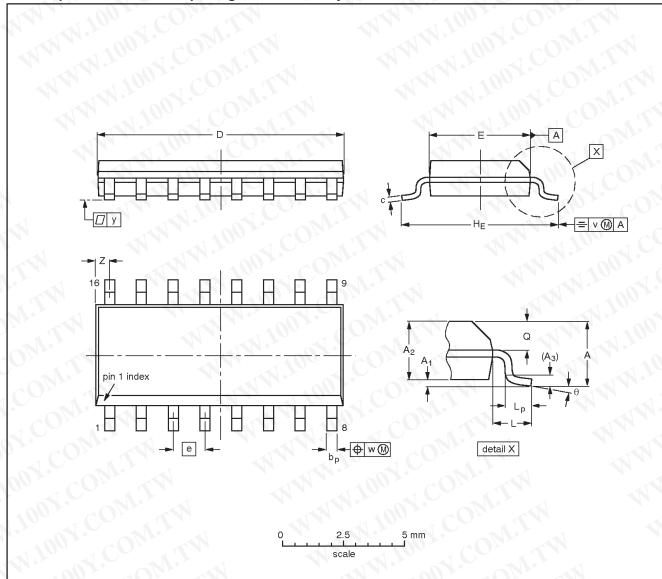
1990 Feb 23

Dual 1-of-4 decoder/demultiplexer

74F139

SO16: plastic small outline package; 16 leads; body width 3.9 mm

SOT109-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UN	IIT	A max.	A ₁	A ₂	A ₃	bp	C	D ⁽¹⁾	E ⁽¹⁾	e	HE	L	Lp	Q	v	W	у	Z ⁽¹⁾	θ
m	m	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	10.0 9.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
incl	nes	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.39 0.38	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016		0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFERE	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE
SOT109-1	076E07S	MS-012AC			95-01-23 97-05-22

1990 Feb 23 7

Dual 1-of-4 decoder/demultiplexer

74F139

Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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^[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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